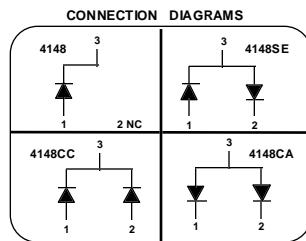
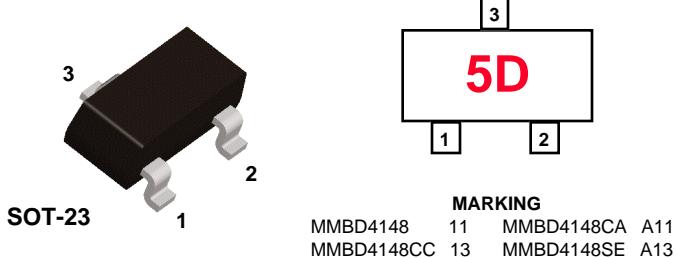




MMBD4148 / SE / CC / CA



High Conductance Ultra Fast Diode

Sourced from Process 1P.

Absolute Maximum Ratings*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
W_{IV}	Working Inverse Voltage	75	V
I_o	Average Rectified Current	200	mA
I_F	DC Forward Current	600	mA
i_f	Recurrent Peak Forward Current	700	mA
$i_f(\text{surge})$	Peak Forward Surge Current Pulse width = 1.0 second Pulse width = 1.0 microsecond	1.0 2.0	A A
T_{stg}	Storage Temperature Range	-55 to +150	°C
T_J	Operating Junction Temperature	150	°C

* These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150 degrees C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations

Thermal Characteristics

TA = 25°C unless otherwise noted

Symbol	Characteristic	Max	Units
			MMBD4148/SE/CC/CA*
P_D	Total Device Dissipation Derate above 25°C	350 2.8	mW mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	357	°C/W

* Device mounted on glass epoxy PCB 1.6" X 1.6" X 0.06"; mounting pad for the collector lead min. 0.93 in²

High Conductance Low Leakage Diode

(continued)

Electrical Characteristics

TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
B_V	Breakdown Voltage	$I_R = 100 \mu A$ $I_R = 5.0 \mu A$	100 75		V V
I_R	Reverse Current	$V_R = 20 V$ $V_R = 20 V, T_A = 150^\circ C$ $V_R = 75 V$		25 50 5.0	nA μA μA
V_F	Forward Voltage	$I_F = 10 mA$		1.0	V
C_O	Diode Capacitance	$V_R = 0, f = 1.0 \text{ MHz}$		4.0	pF
T_{RR}	Reverse Recovery Time	$I_F = 10 mA, V_R = 6.0 V$, $I_{RR} = 1.0 mA, R_L = 100\Omega$		4.0	nS